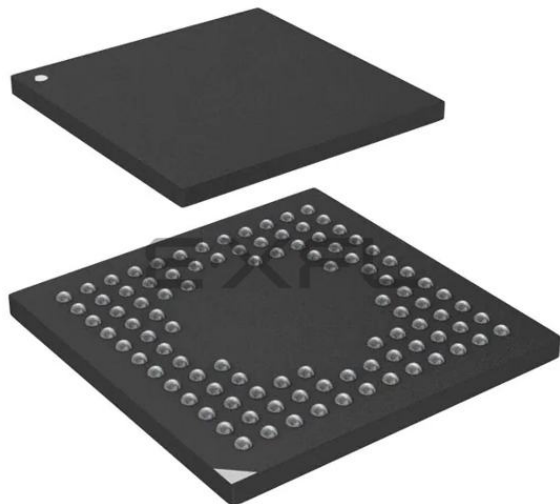




Welcome to [E-XFL.COM](#)

What is "[Embedded - Microcontrollers](#)"?

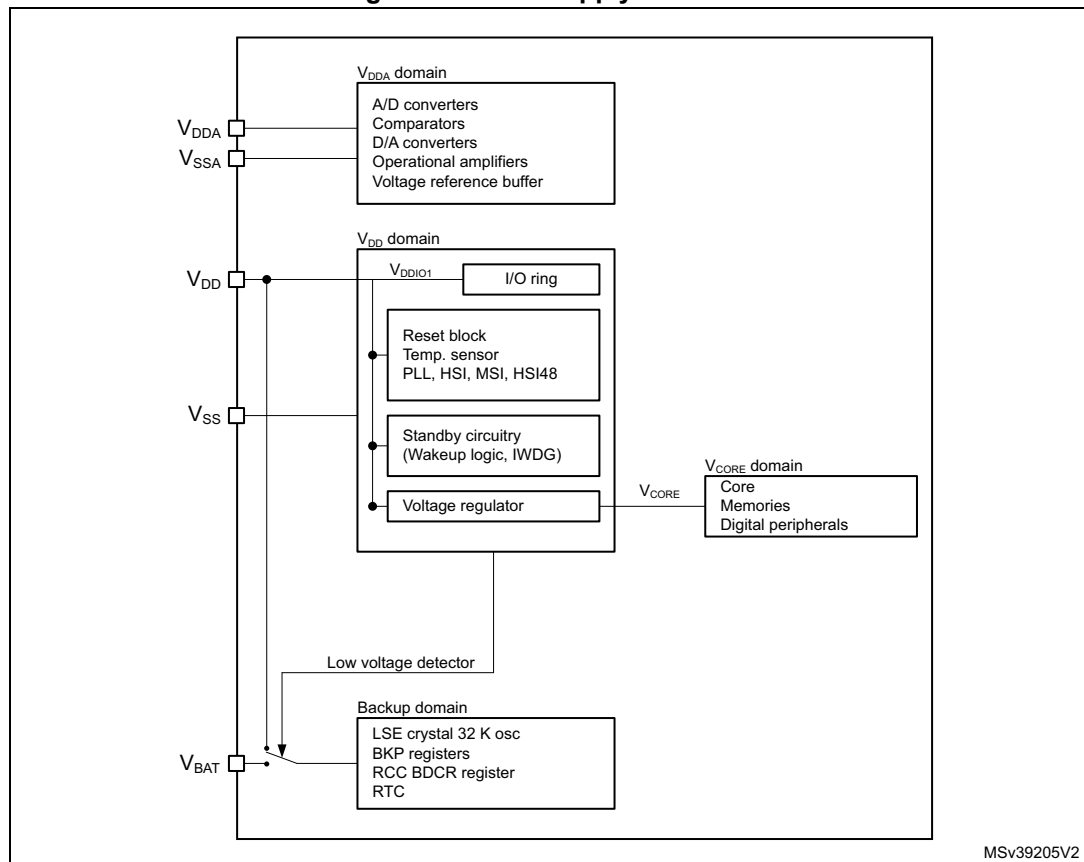
"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex® -M4
Core Size	32-Bit Single-Core
Speed	80MHz
Connectivity	CANbus, I ² C, IrDA, LINbus, MMC/SD, QSPI, SAI, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, PWM, WDT
Number of I/O	83
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	160K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 16x12b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-UFBGA
Supplier Device Package	100-UFBGA (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32l451vei6

Figure 2. Power supply overview



During power-up and power-down phases, the following power sequence requirements must be respected:

- When V_{DD} is below 1 V, other power supplies (V_{DDA}) must remain below $V_{DD} + 300$ mV.
- When V_{DD} is above 1 V, all power supplies are independent.

During the power-down phase, V_{DD} can temporarily become lower than other supplies only if the energy provided to the MCU remains below 1 mJ; this allows external decoupling capacitors to be discharged with different time constants during the power-down transient phase.

3.9.3 Voltage regulator

Two embedded linear voltage regulators supply most of the digital circuitries: the main regulator (MR) and the low-power regulator (LPR).

- The MR is used in the Run and Sleep modes and in the Stop 0 mode.
- The LPR is used in Low-Power Run, Low-Power Sleep, Stop 1 and Stop 2 modes. It is also used to supply the 32 Kbyte SRAM2 in Standby with SRAM2 retention.
- Both regulators are in power-down in Standby and Shutdown modes: the regulator output is in high impedance, and the kernel circuitry is powered down thus inducing zero consumption.

The ultralow-power STM32L451xx supports dynamic voltage scaling to optimize its power consumption in run mode. The voltage from the Main Regulator that supplies the logic (V_{CORE}) can be adjusted according to the system's maximum operating frequency.

There are two power consumption ranges:

- Range 1 with the CPU running at up to 80 MHz.
- Range 2 with a maximum CPU frequency of 26 MHz. All peripheral clocks are also limited to 26 MHz.

The V_{CORE} can be supplied by the low-power regulator, the main regulator being switched off. The system is then in Low-power run mode.

- Low-power run mode with the CPU running at up to 2 MHz. Peripherals with independent clock can be clocked by HSI16.

3.9.4 Low-power modes

The ultra-low-power STM32L451xx supports seven low-power modes to achieve the best compromise between low-power consumption, short startup time, available peripherals and available wakeup sources.



Table 4. STM32L451xx modes overview

Mode	Regulator ⁽¹⁾	CPU	Flash	SRAM	Clocks	DMA & Peripherals ⁽²⁾	Wakeup source	Consumption ⁽³⁾	Wakeup time
Run	MR range 1	Yes	ON ⁽⁴⁾	ON	Any	All	N/A	94 µA/MHz	N/A
	MR range2					All except RNG		85 µA/MHz	
LPRun	LPR	Yes	ON ⁽⁴⁾	ON	Any except PLL	All except RNG	N/A	95 µA/MHz	to Range 1: 4 µs to Range 2: 64 µs
Sleep	MR range 1	No	ON ⁽⁴⁾	ON ⁽⁵⁾	Any	All	Any interrupt or event	27 µA/MHz	6 cycles
	MR range2					All except RNG		27 µA/MHz	
LPSleep	LPR	No	ON ⁽⁴⁾	ON ⁽⁵⁾	Any except PLL	All except RNG	Any interrupt or event	38 µA/MHz	6 cycles
Stop 0	MR Range 1	No	OFF	ON	LSE LSI	BOR, PVD, PVM RTC, IWDG COMPx (x=1,2) DAC1 OPAMPx (x=1) USARTx (x=1...3) ⁽⁶⁾ UART4 ⁽⁶⁾ LPUART1 ⁽⁶⁾ I2Cx (x=1...4) ⁽⁷⁾ LPTIMx (x=1,2) *** All other peripherals are frozen.	Reset pin, all I/Os BOR, PVD, PVM RTC, IWDG COMPx (x=1..2) USARTx (x=1...3) ⁽⁶⁾ UART4 ⁽⁶⁾ LPUART1 ⁽⁶⁾ I2Cx (x=1...4) ⁽⁷⁾ LPTIMx (x=1,2)	125 µA	2.47 µs in SRAM 4.1 µs in Flash
	MR Range 2							125 µA	

Table 5. Functionalities depending on the working mode⁽¹⁾ (continued)

Peripheral	Run	Sleep	Low-power run	Low-power sleep	Stop 0/1		Stop 2		Standby		Shutdown		VBAT
					-	Wakeup capability	-	Wakeup capability	-	Wakeup capability	-	Wakeup capability	
CRC calculation unit	O	O	O	O	-	-	-	-	-	-	-	-	-
GPIOs	O	O	O	O	O	O	O	O	(9) 5 pins (10)	(11) 5 pins (10)	-	-	-

1. Legend: Y = Yes (Enable). O = Optional (Disable by default. Can be enabled by software). - = Not available.
2. The Flash can be configured in power-down mode. By default, it is not in power-down mode.
3. The SRAM clock can be gated on or off.
4. SRAM2 content is preserved when the bit RRS is set in PWR_CR3 register.
5. Some peripherals with wakeup from Stop capability can request HSI16 to be enabled. In this case, HSI16 is woken up by the peripheral, and only feeds the peripheral which requested it. HSI16 is automatically put off when the peripheral does not need it anymore.
6. UART and LPUART reception is functional in Stop mode, and generates a wakeup interrupt on Start, address match or received frame event.
7. I2C address detection is functional in Stop mode, and generates a wakeup interrupt in case of address match.
8. Voltage scaling Range 1 only.
9. I/Os can be configured with internal pull-up, pull-down or floating in Standby mode.
10. The I/Os with wakeup from Standby/Shutdown capability are: PA0, PC13, PE6, PA2, PC5.
11. I/Os can be configured with internal pull-up, pull-down or floating in Shutdown mode but the configuration is lost when exiting the Shutdown mode.

3.9.5 Reset mode

In order to improve the consumption under reset, the I/Os state under and after reset is “analog state” (the I/O schmitt trigger is disable). In addition, the internal reset pull-up is deactivated when the reset source is internal.

3.9.6 VBAT operation

The VBAT pin allows to power the device VBAT domain from an external battery, an external supercapacitor, or from V_{DD} when no external battery and an external supercapacitor are present. The VBAT pin supplies the RTC with LSE and the backup registers. Three anti-tamper detection pins are available in VBAT mode.

VBAT operation is automatically activated when V_{DD} is not present.

An internal VBAT battery charging circuit is embedded and can be activated when V_{DD} is present.

Note: *When the microcontroller is supplied from VBAT, external interrupts and RTC alarm/events do not exit it from VBAT operation.*

3.25 Inter-integrated circuit interface (I²C)

The device embeds four I2C. Refer to [Table 12: I2C implementation](#) for the features implementation.

The I²C bus interface handles communications between the microcontroller and the serial I²C bus. It controls all I²C bus-specific sequencing, protocol, arbitration and timing.

The I2C peripheral supports:

- I²C-bus specification and user manual rev. 5 compatibility:
 - Slave and master modes, multimaster capability
 - Standard-mode (Sm), with a bitrate up to 100 kbit/s
 - Fast-mode (Fm), with a bitrate up to 400 kbit/s
 - Fast-mode Plus (Fm+), with a bitrate up to 1 Mbit/s and 20 mA output drive I/Os
 - 7-bit and 10-bit addressing mode, multiple 7-bit slave addresses
 - Programmable setup and hold times
 - Optional clock stretching
- System Management Bus (SMBus) specification rev 2.0 compatibility:
 - Hardware PEC (Packet Error Checking) generation and verification with ACK control
 - Address resolution protocol (ARP) support
 - SMBus alert
- Power System Management Protocol (PMBus™) specification rev 1.1 compatibility
- Independent clock: a choice of independent clock sources allowing the I2C communication speed to be independent from the PCLK reprogramming. Refer to [Figure 4: Clock tree](#).
- Wakeup from Stop mode on address match
- Programmable analog and digital noise filters
- 1-byte buffer with DMA capability

Table 12. I2C implementation

I2C features ⁽¹⁾	I2C1	I2C2	I2C3	I2C4
Standard-mode (up to 100 kbit/s)	X	X	X	X
Fast-mode (up to 400 kbit/s)	X	X	X	X
Fast-mode Plus with 20mA output drive I/Os (up to 1 Mbit/s)	X	X	X	X
Programmable analog and digital noise filters	X	X	X	X
SMBus/PMBus hardware support	X	X	X	X
Independent clock	X	X	X	X
Wakeup from Stop 1 mode on address match	X	X	X	X
Wakeup from Stop 2 mode on address match	-	-	X	-

1. X: supported

Table 16. STM32L451xx pin definitions (continued)

Pin Number						Pin name (function after reset)	Pin type	I/O structure	Notes	Pin functions	
UFQFPN48	WLCSP64	LQFP64	UFBGA64	LQFP100	UFBGA100					Alternate functions	Additional functions
-	D5	9	E2	16	J2	PC1	I/O	FT_fa	-	TRACED0, LPTIM1_OUT, I2C4_SDA, I2C3_SDA, LPUART1_TX, EVENTOUT	ADC1_IN2
-	D6	10	F2	17	J3	PC2	I/O	FT_a	-	LPTIM1_IN2, SPI2_MISO, DFSDM1_CKOUT, EVENTOUT	ADC1_IN3
-	E7	11	G1	18	K2	PC3	I/O	FT_a	-	LPTIM1_ETR, SPI2_MOSI, SAI1_SD_A, LPTIM2_ETR, EVENTOUT	ADC1_IN4
-	-	-	-	19	J1	VSSA	S	-	-	-	-
-	-	-	-	20	K1	VREF-	S	-	-	-	-
8	G8	12	F1	-	-	VSSA/ VREF-	S	-	-	-	-
-	-	-	-	21	L1	VREF+	S	-	-	-	VREFBUF_OUT
-	-	-	-	22	M1	VDDA	S	-	-	-	-
9	F7	13	H1	-	-	VDDA/ VREF+	S	-	-	-	-
10	H8	14	G2	23	L2	PA0	I/O	FT_a	-	TIM2_CH1, USART2_CTS, UART4_TX, COMP1_OUT, SAI1_EXTCLK, TIM2_ETR, EVENTOUT	OPAMP1_VINP, COMP1_INM, ADC1_IN5, RTC_TAMP2, WKUP1
11	E6	15	H2	24	M2	PA1	I/O	FT_a	-	TIM2_CH2, I2C1_SMBA, SPI1_SCK, USART2_RTS_DE, UART4_RX, TIM15_CH1N, EVENTOUT	OPAMP1_VINM, COMP1_INP, ADC1_IN6
12	G7	16	F3	25	K3	PA2	I/O	FT_a	-	TIM2_CH3, USART2_TX, LPUART1_TX, QUADSPI_BK1_NCS, COMP2_OUT, TIM15_CH1, EVENTOUT	COMP2_INM, ADC1_IN7, WKUP4, LSCO
13	F6	17	G3	26	L3	PA3	I/O	TT_a	-	TIM2_CH4, USART2_RX, LPUART1_RX, QUADSPI_CLK, SAI1_MCLK_A, TIM15_CH2, EVENTOUT	OPAMP1_VOUT, COMP2_INP, ADC1_IN8
-	-	18	C2	27	E3	VSS	S	-	-	-	-
-	H7	19	D2	28	H3	VDD	S	-	-	-	-

Table 16. STM32L451xx pin definitions (continued)

Pin Number						Pin name (function after reset)	Pin type	I/O structure	Notes	Pin functions	
UFQFPN48	WLCSP64	LQFP64	UFBGA64	LQFP100	UFBGA100					Alternate functions	Additional functions
14	G6	20	H3	29	M3	PA4	I/O	TT_a	-	SPI1_NSS, SPI3_NSS, USART2_CK, SAI1_FS_B, LPTIM2_OUT, EVENTOUT	COMP1_INM, COMP2_INM, ADC1_IN9, DAC1_OUT1
15	F5	21	F4	30	K4	PA5	I/O	TT_a	-	TIM2_CH1, TIM2_ETR, SPI1_SCK, DFSDM1_CKOUT, LPTIM2_ETR, EVENTOUT	COMP1_INM, COMP2_INM, ADC1_IN10
16	H6	22	G4	31	L4	PA6	I/O	FT_a	-	TIM1_BKIN, TIM3_CH1, SPI1_MISO, COMP1_OUT, USART3_CTS, LPUART1_CTS, QUADSPI_BK1_IO3, TIM1_BKIN_COMP2, TIM16_CH1, EVENTOUT	ADC1_IN11
17	E5	23	H4	32	M4	PA7	I/O	FT_fa	-	TIM1_CH1N, TIM3_CH2, I2C3_SCL, SPI1_MOSI, DFSDM1_DATIN0, QUADSPI_BK1_IO2, COMP2_OUT, EVENTOUT	ADC1_IN12
-	E4	24	H5	33	K5	PC4	I/O	FT_a	-	USART3_TX, EVENTOUT	COMP1_INM, ADC1_IN13
-	G5	25	H6	34	L5	PC5	I/O	FT_a	-	USART3_RX, EVENTOUT	COMP1_INP, ADC1_IN14, WKUP5
18	H5	26	F5	35	M5	PB0	I/O	FT_a	-	TIM1_CH2N, TIM3_CH3, SPI1_NSS, DFSDM1_CKIN0, USART3_CK, QUADSPI_BK1_IO1, COMP1_OUT, SAI1_EXTCLK, EVENTOUT	ADC1_IN15
19	F4	27	G5	36	M6	PB1	I/O	FT_a	-	TIM1_CH3N, TIM3_CH4, DFSDM1_DATIN0, USART3_RTS_DE, LPUART1_RTS_DE, QUADSPI_BK1_IO0, LPTIM2_IN1, EVENTOUT	COMP1_INM, ADC1_IN16
20	G4	28	G6	37	L6	PB2	I/O	FT_a	-	RTC_OUT, LPTIM1_OUT, I2C3_SMBA, DFSDM1_CKIN0, EVENTOUT	COMP1_INP
-	-	-	-	38	M7	PE7	I/O	FT	-	TIM1_ETR, DFSDM1_DATIN2, SAI1_SD_B, EVENTOUT	-

Table 16. STM32L451xx pin definitions (continued)

Pin Number						Pin name (function after reset)	Pin type	I/O structure	Notes	Pin functions	
UFQFPN48	WLCSP64	LQFP64	UFBGA64	LQFP100	UFBGA100					Alternate functions	Additional functions
-	-	-	-	39	L7	PE8	I/O	FT	-	TIM1_CH1N, DFSDM1_CKIN2, SAI1_SCK_B, EVENTOUT	-
-	-	-	-	40	M8	PE9	I/O	FT	-	TIM1_CH1, DFSDM1_CKOUT, SAI1_FS_B, EVENTOUT	-
-	-	-	-	41	L8	PE10	I/O	FT	-	TIM1_CH2N, TSC_G5_IO1, QUADSPI_CLK, SAI1_MCLK_B, EVENTOUT	-
-	-	-	-	42	M9	PE11	I/O	FT	-	TIM1_CH2, TSC_G5_IO2, QUADSPI_BK1_NCS, EVENTOUT	-
-	-	-	-	43	L9	PE12	I/O	FT	-	TIM1_CH3N, SPI1_NSS, TSC_G5_IO3, QUADSPI_BK1_IO0, EVENTOUT	-
-	-	-	-	44	M10	PE13	I/O	FT	-	TIM1_CH3, SPI1_SCK, TSC_G5_IO4, QUADSPI_BK1_IO1, EVENTOUT	-
-	-	-	-	45	M11	PE14	I/O	FT	-	TIM1_CH4, TIM1_BKIN2, TIM1_BKIN2_COMP2, SPI1_MISO, QUADSPI_BK1_IO2, EVENTOUT	-
-	-	-	-	46	M12	PE15	I/O	FT	-	TIM1_BKIN, TIM1_BKIN_COMP1, SPI1_MOSI, QUADSPI_BK1_IO3, EVENTOUT	-
21	H4	29	G7	47	L10	PB10	I/O	FT_f	-	TIM2_CH3, I2C4_SCL, I2C2_SCL, SPI2_SCK, USART3_TX, LPUART1_RX, TSC_SYNC, QUADSPI_CLK, COMP1_OUT, SAI1_SCK_A, EVENTOUT	-
22	H3	30	H7	48	L11	PB11	I/O	FT_f	-	TIM2_CH4, I2C4_SDA, I2C2_SDA, USART3_RX, LPUART1_TX, QUADSPI_BK1_NCS, COMP2_OUT, EVENTOUT	-

Table 18. Alternate function AF8 to AF15⁽¹⁾ (continued)

Port		AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
		UART4/ LPUART1/ CAN1	CAN1/TSC	CAN1/ QUADSPI	-	SDMMC1/ COMP1/ COMP2	SAI1	TIM2/TIM15/ TIM16/LPTIM2	EVENTOUT
Port C	PC0	LPUART1_RX	-	-	-	-	-	LPTIM2_IN1	EVENTOUT
	PC1	LPUART1_TX	-	-	-	-	-	-	EVENTOUT
	PC2	-	-	-	-	-	-	-	EVENTOUT
	PC3	-	-	-	-	-	SAI1_SD_A	LPTIM2_ETR	EVENTOUT
	PC4	-	-	-	-	-	-	-	EVENTOUT
	PC5	-	-	-	-	-	-	-	EVENTOUT
	PC6	-	TSC_G4_IO1	-	-	SDMMC1_D6	-	-	EVENTOUT
	PC7	-	TSC_G4_IO2	-	-	SDMMC1_D7	-	-	EVENTOUT
	PC8	-	TSC_G4_IO3	-	-	SDMMC1_D0	-	-	EVENTOUT
	PC9	-	TSC_G4_IO4	-	-	SDMMC1_D1	-	-	EVENTOUT
	PC10	UART4_TX	TSC_G3_IO2	-	-	SDMMC1_D2	-	-	EVENTOUT
	PC11	UART4_RX	TSC_G3_IO3	-	-	SDMMC1_D3	-	-	EVENTOUT
	PC12	-	TSC_G3_IO4	-	-	SDMMC1_CK	-	-	EVENTOUT
	PC13	-	-	-	-	-	-	-	EVENTOUT
	PC14	-	-	-	-	-	-	-	EVENTOUT
	PC15	-	-	-	-	-	-	-	EVENTOUT

Table 18. Alternate function AF8 to AF15⁽¹⁾ (continued)

Port		AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
		UART4/ LPUART1/ CAN1	CAN1/TSC	CAN1/ QUADSPI	-	SDMMC1/ COMP1/ COMP2	SAI1	TIM2/TIM15/ TIM16/LPTIM2	EVENTOUT
Port E	PE0	-	-	-	-	-	-	TIM16_CH1	EVENTOUT
	PE1	-	-	-	-	-	-	-	EVENTOUT
	PE2	-	TSC_G7_IO1	-	-	-	SAI1_MCLK_A	-	EVENTOUT
	PE3	-	TSC_G7_IO2	-	-	-	SAI1_SD_B	-	EVENTOUT
	PE4	-	TSC_G7_IO3	-	-	-	SAI1_FS_A	-	EVENTOUT
	PE5	-	TSC_G7_IO4	-	-	-	SAI1_SCK_A	-	EVENTOUT
	PE6	-	-	-	-	-	SAI1_SD_A	-	EVENTOUT
	PE7	-	-	-	-	-	SAI1_SD_B	-	EVENTOUT
	PE8	-	-	-	-	-	SAI1_SCK_B	-	EVENTOUT
	PE9	-	-	-	-	-	SAI1_FS_B	-	EVENTOUT
	PE10	-	TSC_G5_IO1	QUADSPI_CLK	-	-	SAI1_MCLK_B	-	EVENTOUT
	PE11	-	TSC_G5_IO2	QUADSPI_ BK1_NCS	-	-	-	-	EVENTOUT
	PE12	-	TSC_G5_IO3	QUADSPI_ BK1_IO0	-	-	-	-	EVENTOUT
	PE13	-	TSC_G5_IO4	QUADSPI_ BK1_IO1	-	-	-	-	EVENTOUT
	PE14	-	-	QUADSPI_ BK1_IO2	-	-	-	-	EVENTOUT
	PE15	-	-	QUADSPI_ BK1_IO3	-	-	-	-	EVENTOUT
Port H	PH0	-	-	-	-	-	-	-	EVENTOUT
	PH1	-	-	-	-	-	-	-	EVENTOUT
	PH3	-	-	-	-	-	-	-	EVENTOUT

Table 19. STM32L451xx memory map and peripheral register boundary addresses⁽¹⁾
(continued)

Bus	Boundary address	Size(bytes)	Peripheral
APB1	0x4000 2800 - 0x4000 2BFF	1 KB	RTC
	0x4000 1400 - 0x4000 27FF	5 KB	Reserved
	0x4000 1000 - 0x4000 13FF	1 KB	TIM6
	0x4000 0800 - 0x4000 0FFF	2 KB	Reserved
	0x4000 0400 - 0x4000 07FF	1 KB	TIM3
	0x4000 0000 - 0x4000 03FF	1 KB	TIM2

1. The gray color is used for reserved boundary addresses.

Table 37. Current consumption in Stop 0

Symbol	Parameter	Conditions	TYP					MAX ⁽¹⁾					Unit
		V _{DD}	25 °C	55 °C	85 °C	105 °C	125 °C	25 °C	55 °C	85 °C	105 °C	125 °C	
I _{DD_ALL} (Stop 0)	Supply current in Stop 0 mode, RTC disabled	1.8 V	125	150	240	390	645	145	190	350	600	1150	μA
		2.4 V	125	150	240	390	645	150	195	355	605	1150	
		3 V	125	150	245	395	650	155	195	360	610	1150	
		3.6 V	125	155	245	400	655	155	200	365	615	1150 ⁽²⁾	

1. Guaranteed by characterization results, unless otherwise specified.

2. Guaranteed by test in production.

Table 38. Current consumption in Standby mode

Symbol	Parameter	Conditions		TYP					MAX ⁽¹⁾					Unit
		-	V _{DD}	25 °C	55 °C	85 °C	105 °C	125 °C	25 °C	55 °C	85 °C	105 °C	125 °C	
I _{DD_ALL} (Standby)	Supply current in Standby mode (backup registers retained), RTC disabled	no independent watchdog	1.8 V	100	270	1200	3300	8650	205	650	3250	9250	25000	nA
			2.4 V	110	305	1400	3850	10000	225	750	3750	11000	29000	
			3 V	125	360	1650	4550	12000	290	950	4450	13000	33500	
			3.6 V	160	445	2000	5500	14500	355	1150	5250	15000	38500	
		with independent watchdog	1.8 V	265	435	1350	3450	8700	-	-	-	-	-	
			2.4 V	335	540	1650	4100	10500	-	-	-	-	-	
			3 V	420	655	1950	4850	12500	-	-	-	-	-	
			3.6 V	580	895	2450	5950	14500	-	-	-	-	-	
I _{DD_ALL} (Standby with RTC)	Supply current in Standby mode (backup registers retained), RTC enabled	RTC clocked by LSI, no independent watchdog	1.8 V	345	505	1400	3450	8600	720	1150	3750	9550	25000	nA
			2.4 V	420	620	1650	4050	10000	875	1450	4400	11500	29000	
			3 V	510	745	2000	4750	12000	1070	1700	5100	13500	34000	
			3.6 V	635	915	2450	5900	14500	1320	2100	6000	15500	39000	
		RTC clocked by LSI, with independent watchdog	1.8 V	375	540	1450	3550	8800	-	-	-	-	-	
			2.4 V	490	690	1800	4250	10500	-	-	-	-	-	
			3 V	620	860	2150	5100	12500	-	-	-	-	-	
			3.6 V	845	1150	2700	6200	15000	-	-	-	-	-	
		RTC clocked by LSE bypassed at 32768Hz	1.8 V	395	-	-	-	-	-	-	-	-	-	nA
			2.4 V	500	-	-	-	-	-	-	-	-	-	
			3 V	625	-	-	-	-	-	-	-	-	-	
			3.6 V	795	-	-	-	-	-	-	-	-	-	
		RTC clocked by LSE quartz ⁽²⁾ in low drive mode	1.8 V	375	550	1500	3550	8800	-	-	-	-	-	
			2.4 V	460	665	1750	4250	10500	-	-	-	-	-	
			3 V	565	810	2100	5050	12500	-	-	-	-	-	
			3.6 V	720	1000	2600	5900	15000	-	-	-	-	-	

Low-speed external user clock generated from an external source

In bypass mode the LSE oscillator is switched off and the input pin is a standard GPIO.

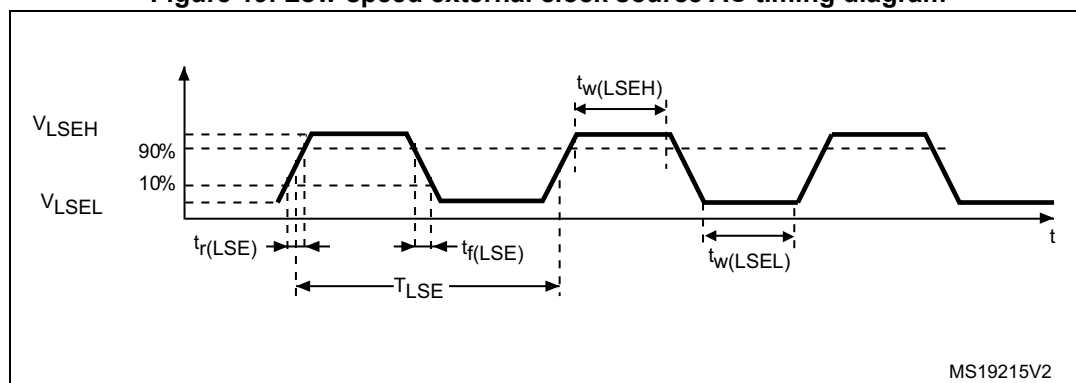
The external clock signal has to respect the I/O characteristics in [Section 6.3.14](#). However, the recommended clock input waveform is shown in [Figure 19](#).

Table 46. Low-speed external user clock characteristics⁽¹⁾

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{LSE_ext}	User external clock source frequency	-	-	32.768	1000	kHz
V_{LSEH}	OSC32_IN input pin high level voltage	-	$0.7 V_{DDIOx}$	-	V_{DDIOx}	V
V_{LSEL}	OSC32_IN input pin low level voltage	-	V_{SS}	-	$0.3 V_{DDIOx}$	
$t_{w(LSEH)}$ $t_{w(LSEL)}$	OSC32_IN high or low time	-	250	-	-	ns

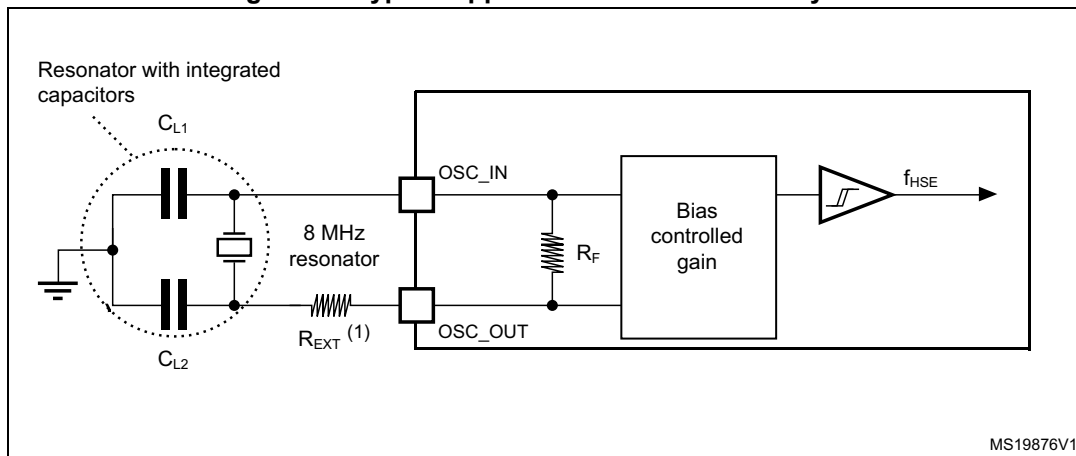
1. Guaranteed by design.

Figure 19. Low-speed external clock source AC timing diagram



Note: For information on selecting the crystal, refer to the application note AN2867 “Oscillator design guide for ST microcontrollers” available from the ST website www.st.com.

Figure 20. Typical application with an 8 MHz crystal



1. R_{EXT} value depends on the crystal characteristics.

Low-speed external clock generated from a crystal resonator

The low-speed external (LSE) clock can be supplied with a 32.768 kHz crystal resonator oscillator. All the information given in this paragraph are based on design simulation results obtained with typical external components specified in [Table 48](#). In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

Table 48. LSE oscillator characteristics ($f_{LSE} = 32.768$ kHz)⁽¹⁾

Symbol	Parameter	Conditions ⁽²⁾	Min	Typ	Max	Unit
$I_{DD(LSE)}$	LSE current consumption	LSEDRV[1:0] = 00 Low drive capability	-	250	-	nA
		LSEDRV[1:0] = 01 Medium low drive capability	-	315	-	
		LSEDRV[1:0] = 10 Medium high drive capability	-	500	-	
		LSEDRV[1:0] = 11 High drive capability	-	630	-	
$G_{m_{critmax}}$	Maximum critical crystal gm	LSEDRV[1:0] = 00 Low drive capability	-	-	0.5	$\mu A/V$
		LSEDRV[1:0] = 01 Medium low drive capability	-	-	0.75	
		LSEDRV[1:0] = 10 Medium high drive capability	-	-	1.7	
		LSEDRV[1:0] = 11 High drive capability	-	-	2.7	
$t_{SU(LSE)}^{(3)}$	Startup time	V_{DD} is stabilized	-	2	-	s

6.3.14 I/O port characteristics

General input/output characteristics

Unless otherwise specified, the parameters given in [Table 61](#) are derived from tests performed under the conditions summarized in [Table 23: General operating conditions](#). All I/Os are designed as CMOS- and TTL-compliant.

Table 61. I/O static characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{IL}^{(1)}$	I/O input low level voltage	$1.62\text{ V} < V_{DDIOx} < 3.6\text{ V}$	-	-	$0.3 \times V_{DDIOx}^{(2)}$	V
	I/O input low level voltage	$1.62\text{ V} < V_{DDIOx} < 3.6\text{ V}$	-	-	$0.39 \times V_{DDIOx} - 0.06^{(3)}$	
	I/O input low level voltage	$1.08\text{ V} < V_{DDIOx} < 1.62\text{ V}$	-	-	$0.43 \times V_{DDIOx} - 0.1^{(3)}$	
$V_{IH}^{(1)}$	I/O input high level voltage	$1.62\text{ V} < V_{DDIOx} < 3.6\text{ V}$	$0.7 \times V_{DDIOx}^{(2)}$	-	-	V
	I/O input high level voltage	$1.62\text{ V} < V_{DDIOx} < 3.6\text{ V}$	$0.49 \times V_{DDIOx} + 0.26^{(3)}$	-	-	
	I/O input high level voltage	$1.08\text{ V} < V_{DDIOx} < 1.62\text{ V}$	$0.61 \times V_{DDIOx} + 0.05^{(3)}$	-	-	
$V_{hys}^{(3)}$	TT_xx, FT_XXX and NRST I/O input hysteresis	$1.62\text{ V} < V_{DDIOx} < 3.6\text{ V}$	-	200	-	mV
I_{lkg}	FT_xx input leakage current ⁽³⁾⁽⁴⁾	$V_{IN} \leq \text{Max}(V_{DDXXX})^{(5)(6)}$	-	-	± 100	nA
		$\text{Max}(V_{DDXXX}) \leq V_{IN} \leq \text{Max}(V_{DDXXX}) + 1\text{ V}^{(5)(6)}$	-	-	$650^{(3)(7)}$	
		$\text{Max}(V_{DDXXX}) + 1\text{ V} < V_{IN} \leq 5.5\text{ V}^{(3)(6)}$	-	-	$200^{(7)}$	
	PA11, PA12, and PC3 I/O	$V_{IN} \leq \text{Max}(V_{DDXXX})^{(5)(6)}$	-	-	± 150	
		$\text{Max}(V_{DDXXX}) \leq V_{IN} \leq \text{Max}(V_{DDXXX}) + 1\text{ V}^{(5)(6)}$	-	-	$2500^{(3)}$	
		$\text{Max}(V_{DDXXX}) + 1\text{ V} < V_{IN} \leq 5.5\text{ V}^{(5)(6)}$	-	-	250	
	TT_xx input leakage current	$V_{IN} \leq \text{Max}(V_{DDXXX})^{(7)}$	-	-	± 150	
		$\text{Max}(V_{DDXXX}) \leq V_{IN} < 3.6\text{ V}^{(7)}$	-	-	$2000^{(3)}$	
R_{PU}	Weak pull-up equivalent resistor ⁽⁸⁾	$V_{IN} = V_{SS}$	25	40	55	kΩ
R_{PD}	Weak pull-down equivalent resistor ⁽⁸⁾	$V_{IN} = V_{DDIOx}$	25	40	55	kΩ
C_{IO}	I/O pin capacitance	-	-	5	-	pF

Table 70. ADC accuracy - limited test conditions 2⁽¹⁾(2)(3) (continued)

Sym- bol	Parameter	Conditions ⁽⁴⁾			Min	Typ	Max	Unit
THD	Total harmonic distortion	ADC clock frequency $\leq$ 80 MHz, Sampling rate $\leq$ 5.33 Msps, $2\text{ V} \leq V_{DDA}$	Single ended	Fast channel (max speed)	-	-74	-65	dB
				Slow channel (max speed)	-	-74	-67	
			Differential	Fast channel (max speed)	-	-79	-70	
				Slow channel (max speed)	-	-79	-71	

1. Guaranteed by design.
2. ADC DC accuracy values are measured after internal calibration.
3. ADC accuracy vs. negative Injection Current: Injecting negative current on any analog input pins should be avoided as this significantly reduces the accuracy of the conversion being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to analog pins which may potentially inject negative current.
4. The I/O analog switch voltage booster is enable when $V_{DDA} < 2.4\text{ V}$ (BOOSTEN = 1 in the SYSCFG_CFGR1 when $V_{DDA} < 2.4\text{ V}$). It is disable when $V_{DDA} \geq 2.4\text{ V}$. No oversampling.

Table 74. DAC accuracy⁽¹⁾ (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
SINAD	Signal-to-noise and distortion ratio	DAC output buffer ON CL ≤ 50 pF, RL ≥ 5 kΩ, 1 kHz	-	70.4	-	dB
		DAC output buffer OFF CL ≤ 50 pF, no RL, 1 kHz	-	71	-	
ENOB	Effective number of bits	DAC output buffer ON CL ≤ 50 pF, RL ≥ 5 kΩ, 1 kHz	-	11.4	-	bits
		DAC output buffer OFF CL ≤ 50 pF, no RL, 1 kHz	-	11.5	-	

1. Guaranteed by design.
2. Difference between two consecutive codes - 1 LSB.
3. Difference between measured value at Code i and the value at Code i on a line drawn between Code 0 and last Code 4095.
4. Difference between the value measured at Code (0x001) and the ideal value.
5. Difference between ideal slope of the transfer function and measured slope computed from code 0x000 and 0xFFFF when buffer is OFF, and from code giving 0.2 V and ($V_{REF+} - 0.2$) V when buffer is ON.

Table 87. QUADSPI characteristics in DDR mode⁽¹⁾

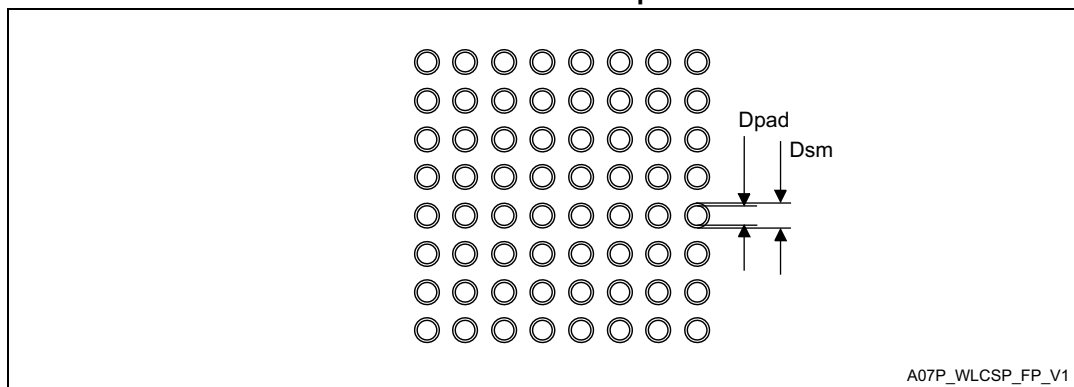
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
F_{CK} $1/t_{(CK)}$	Quad SPI clock frequency	$1.71 < V_{DD} < 3.6 \text{ V}$, $C_{LOAD} = 20 \text{ pF}$ Voltage Range 1	-	-	40	MHz
		$2 < V_{DD} < 3.6 \text{ V}$, $C_{LOAD} = 20 \text{ pF}$ Voltage Range 1	-	-	48	
		$1.71 < V_{DD} < 3.6 \text{ V}$, $C_{LOAD} = 15 \text{ pF}$ Voltage Range 1	-	-	48	
		$1.71 < V_{DD} < 3.6 \text{ V}$ $C_{LOAD} = 20 \text{ pF}$ Voltage Range 2	-	-	26	
$t_{w(CKH)}$	Quad SPI clock high and low time	$f_{AHBCLK} = 48 \text{ MHz}$, presc=0	$t_{(CK)}/2-2$	-	$t_{(CK)}/2$	ns
$t_{w(CKL)}$			$t_{(CK)}/2$	-	$t_{(CK)}/2+2$	
$t_{sr(IN)}$	Data input setup time on rising edge	Voltage Range 1	1	-	-	
		Voltage Range 2	3.5			
$t_{sf(IN)}$	Data input setup time on falling edge	Voltage Range 1	1	-	-	
		Voltage Range 2	1.5			
$t_{hr(IN)}$	Data input hold time on rising edge	Voltage Range 1	6	-	-	
		Voltage Range 2	6.5			
$t_{hf(IN)}$	Data input hold time on falling edge	Voltage Range 1	5.5	-	-	
		Voltage Range 2	5.5			
$t_{vr(OUT)}$	Data output valid time on rising edge	Voltage Range 1	-	5	5.5	
		Voltage Range 2		9.5	14	
$t_{vf(OUT)}$	Data output valid time on falling edge	Voltage Range 1	-	5	8.5	
		Voltage Range 2		15	19	
$t_{hr(OUT)}$	Data output hold time on rising edge	Voltage Range 1	3.5	-	-	
		Voltage Range 2	8	-		
$t_{hf(OUT)}$	Data output hold time on falling edge	Voltage Range 1	3.5	-	-	
		Voltage Range 2	13	-		

1. Guaranteed by characterization results.

Table 97. WLCSP64 - 64-ball, 3.357x3.657 mm 0.4 mm pitch wafer level chip scale mechanical data

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
A	0.525	0.555	0.585	0.0207	0.0219	0.0230
A1	-	0.175	-	-	0.0069	-
A2	-	0.380	-	-	0.0150	-
A3	-	0.025	-	-	0.0010	-
b	0.220	0.250	0.280	0.0087	0.0098	0.0110
D	3.322	3.357	3.392	0.1308	0.1322	0.1335
E	3.622	3.657	3.692	0.1426	0.1440	0.1454
e	-	0.400	-	-	0.0157	-
e1	-	2.800	-	-	0.1102	-
e2	-	2.800	-	-	0.1102	-
F	-	0.278	-	-	0.0109	-
G	-	0.428	-	-	0.0169	-
aaa	-	-	0.100	-	-	0.0039
bbb	-	-	0.100	-	-	0.0039
ccc	-	-	0.100	-	-	0.0039
ddd	-	-	0.050	-	-	0.0020
eee	-	-	0.050	-	-	0.0020

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 53. WLCSP64 - 64-pin, 3.357x3.657 mm 0.4 mm pitch wafer level chip scale recommended footprint

1. Dimensions are expressed in millimeters.